2nd International Workshop on the Sustainable Actions for "Year by Year Aging" under Reliability Investigations in Photovoltaic Modules, 2017
SAYURI-PV 2017

Dear PV colleagues,

The organizing committee of SAYURI-PV 2017 is pleased to inform you that the 2nd International Workshop on the **S**ustainable **A**ctions for "**Y**ear by Year Aging" **u**nder **R**eliability **I**nvestigations in **P**hotov**v**oltaic Modules, 2017 (**SAYURI-PV 2017**) will be held as ***a satellite meeting of the 27th International Photovoltaic Science and Engineering Conference*** (**PVSEC-27**: **http://pvsec-27.com**). Following the previous workshop (SAYURI-PV 2016), we expect international PV technology researchers and experts to share information in this workshop leading to the improvement of PV module reliability to reduce the cost of solar photovoltaic systems and promote investors' confidence in the technology. Presentation slides from the previous workshop are uploaded on our website: https://unit.aist.go.jp/rcpv/cie/workshop/2016_SAYURI-PV/presentation_na/program.html.

Through this 1st circular of "SAYURI-PV 2017", we sincerely ask you to save the dates of this workshop: November 11th‐12th, 2017, which are in the late autumn season. The 2nd circular containing "Registration Information" will be uploaded in June, 2017.

We are looking forward to having lively discussions with you in the most beautiful season of Japan.

[SAYURI-PV 2017]

Date: **November 11th – 12th, 2017**

Venue: **Ryukoku University, Seta Campus (Building 8)**
1-5 Yokotani, Seta Oe-cho, Otsu, Shiga 520-2194, JAPAN
http://www.ryukoku.ac.jp/english2/about/access/seta.html

Topics: *Evaluation methods of materials (including PV cells, polymers, metallization, and others)* to assure the long-term reliability of PV modules, including efforts toward their standardization.

Registration Fee:	Free	**Language:**	English
Registration:	Opens in late June, 2017		
Latest Information:	Check for updates at	https://unit.aist.go.jp/rcpv/cie/index.html	
	Contacts	sayuri-pv-sec-ml@aist.go.jp	